

1. Record Nr.	UNINA9910332529303321
Titolo	Proceedings of the 2016 IEEE 23rd International Symposium on the Physical and Failure Analysis of Integrated Circuits (IPFA) : 18-21 July 2016, Marina Bay Sand, Singapore // sponsored by IEEE [and six others]
Pubbl/distr/stampa	Piscataway, New Jersey : , : Institute of Electrical and Electronics Engineers, , 2016
ISBN	1-4673-8259-0
Descrizione fisica	1 online resource (111 pages)
Disciplina	629.831
Soggetti	Integrated circuits - Reliability Integrated circuits - Testing
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia